



Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: I0104-01 Product Affected: 79RC64T574/79RC64T575 Manufacturing Location Affected: N/A Date Effective: 7/19/01	DATE: 4/19/01	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark <input checked="" type="checkbox"/> Date Code Prefix from "ZB " to "ZD" <input type="checkbox"/> Other
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Contact: Bimla Paul Title: Product Assurance Manager Phone #: 408-654-6419 Fax #: 408-492-8362 E-mail: paul@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples:
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DESCRIPTION AND PURPOSE OF CHANGE:

- Die Technology
- Wafer Fabrication Process
- Assembly Process
- Equipment
- Material
- Testing
- Manufacturing Site
- Data Sheet
- Other Die Revision change from "ZB" (CMOS 10.5) to "ZD" (CMOS 10.5).

RELIABILITY/QUALIFICATION SUMMARY:
Qualification data is attached.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:
 IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT - PCN #: I0104-01

PCN Summary

PCN Type: Die Revision change from "ZB" (CMOS 10.5) to "ZD" (CMOS 10.5).

Forecast or Execute Execute

Planned or Unplanned Planned

Data Sheet Change N/A

Detail of Change Minor design changes were made to improve the overall performance of the device. Data Sheet parameters and device functionality remain unaffected.

Conversion schedule (Estimated)

Sample Availability
Available

Production Shipments
7/19/01

Qualification Results

Test Vehicle: 79RC64T575

	Lot #1 sample/# fails	Lot #2 sample/# fails	Lot #3 sample/# fails
Operating Life Test (Dynamic) (1000 Hrs @ 125°C, Vcc = 2.8V)	77/0	77/0	77/0
Temperature cycling (-65°C to +150°C, 500cyc)	45/0	45/0	45/0
ESD: Human Body Model Mil-Std 883, Method 3015	3/0	N/A	N/A
ESD: Charge Device Model JESD22-C101	3/0	N/A	N/A
Latch-up	10/0	N/A	N/A

Characterization Data:

Characterization Data is available upon request.